

Search Notes

Application/Control No.

10/692,773

Examiner

Eric B. Chen

Applicant(s)/Patent under
Reexamination

LEE, HEON

Art Unit

1765

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 216 | 18,22,38 | 6/16/2005 | EC |
| 216 | 39,46,67 | 6/16/2005 | EC |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| Performed inventor search for double patenting | 6/16/2005 | EC |
| EAST search | 6/16/2005 | EC |
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